



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: WAGGANER et al.

Attorney Docket No.:
LAM1P182/P1183

Application No.: 10/712,410

Examiner: Unassigned

Filed: November 12, 2003

Group: 2818

Title: LINE EDGE ROUGHNESS REDUCTION
FOR TRENCH ETCH

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on March 30, 2004 in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Signed: Sue Funchess
Sue Funchess

**INFORMATION DISCLOSURE STATEMENT
37 CFR §§1.56 AND 1.97(b)**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure

Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 50-0388 (Order No. LAM1P182).

Respectfully submitted,
BEYER WEAVER & THOMAS, LLP



Michael Lee
Registration No. 31,846

P.O. Box 778
Berkeley, CA 94704-0778
(831) 655-2300



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)				Atty Docket No. LAM1P182/P1183	Application No.: 10/712,410
				Applicant: Wagganer et al.	Group 2818
				Filing Date November 12, 2003	

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A	5,658,425	08/19/97	Halman et al.	438	620	06/07/95
	B	6,080,680	06/27/00	Lee et al.	438	727	12/19/97
	C	6,090,304	07/18/00	Zhu et al.	216	79	08/28/97
	D	6,518,174B2	02/11/03	Annapragada et al.	438	637	12/22/00
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication					
	O	Calvin T. Gabriel, et al., "Measuring and Minimizing Line Edge Roughness in BEOL Damascene Dielectric Patterning", 2003 AVS 4th Int'l. Conf. on Microelectronics and Interfaces, March 3-6, Santa Clara, CA, pages 204-207.					
	P						
	Q						
Examiner			Date Considered				

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.